

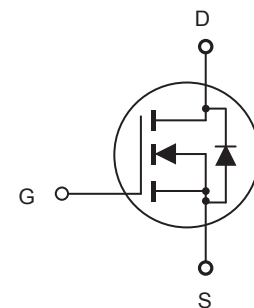


CED6060R/CEU6060R

N-Channel Enhancement Mode Field Effect Transistor

FEATURES

- 60V, 30A, $R_{DS(ON)} = 25m\Omega$ @ $V_{GS} = 10V$.
- Super high dense cell design for extremely low $R_{DS(ON)}$.
- High power and current handling capability.
- Lead free product is acquired.
- TO-251 & TO-252 package.



ABSOLUTE MAXIMUM RATINGS $T_C = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Limit	Units
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	I_D	30	A
Drain Current-Pulsed ^a	I_{DM}	120	A
Maximum Power Dissipation @ $T_C = 25^\circ\text{C}$ - Derate above 25°C	P_D	50	W
		0.34	W/ $^\circ\text{C}$
Single Pulsed Avalanche Energy ^d	E_{AS}	200	mJ
Single Pulsed Avalanche Current ^d	I_{AS}	30	A
Operating and Store Temperature Range	T_J, T_{stg}	-55 to 175	$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	3	$^\circ\text{C/W}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	50	$^\circ\text{C/W}$



CED6060R/CEU6060R

Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	60			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 60V, V_{GS} = 0V$			25	μA
Gate Body Leakage Current, Forward	I_{GSSF}	$V_{GS} = 20V, V_{DS} = 0V$			100	nA
Gate Body Leakage Current, Reverse	I_{GSSR}	$V_{GS} = -20V, V_{DS} = 0V$			-100	nA
On Characteristics ^b						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS} = V_{DS}, I_D = 250\mu A$	2		4	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 24A$			25	m Ω
Dynamic Characteristics ^c						
Forward Transconductance	g_{FS}	$V_{DS} = 10V, I_D = 24A$		19		S
Input Capacitance	C_{iss}	$V_{DS} = 25V, V_{GS} = 0V, f = 1.0\text{ MHz}$		1365		pF
Output Capacitance	C_{oss}			385		pF
Reverse Transfer Capacitance	C_{rss}			90		pF
Switching Characteristics ^c						
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 30V, I_D = 30A, V_{GS} = 10V, R_{GEN} = 7.5\Omega$		18	36	ns
Turn-On Rise Time	t_r			16	32	ns
Turn-Off Delay Time	$t_{d(off)}$			34	68	ns
Turn-Off Fall Time	t_f	$V_{DS} = 48V, I_D = 30A, V_{GS} = 10V$		21	42	ns
Total Gate Charge	Q_g			39.5	52.5	nC
Gate-Source Charge	Q_{gs}			10.4		nC
Gate-Drain Charge	Q_{gd}			14.9		nC
Drain-Source Diode Characteristics and Maximum Ratings						
Drain-Source Diode Forward Current	I_S				30	A
Drain-Source Diode Forward Voltage ^b	V_{SD}	$V_{GS} = 0V, I_S = 24A$			1.3	V
Notes : ^a Repetitive Rating : Pulse width limited by maximum junction temperature. ^b Pulse Test : Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$. ^c Guaranteed by design, not subject to production testing. ^d L = 25 μH , I _{AS} = 30A, V _{DD} = 25V, R _G = 25 Ω , Starting T _J = 25°C						



CED6060R/CEU6060R

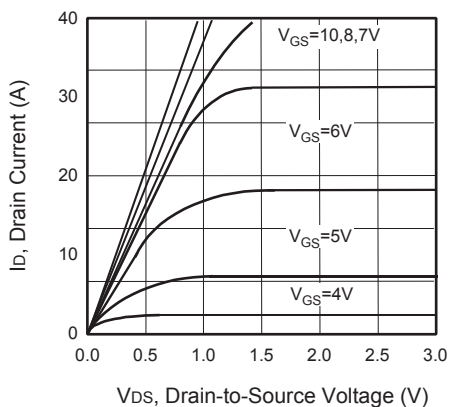


Figure 1. Output Characteristics

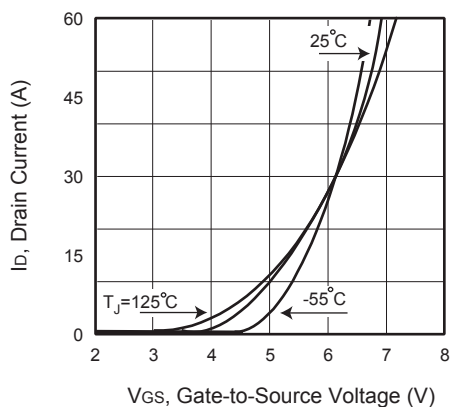


Figure 2. Transfer Characteristics

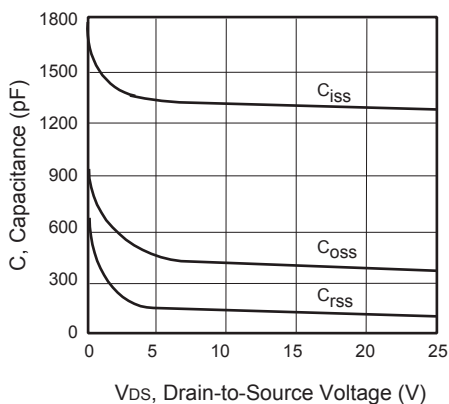


Figure 3. Capacitance

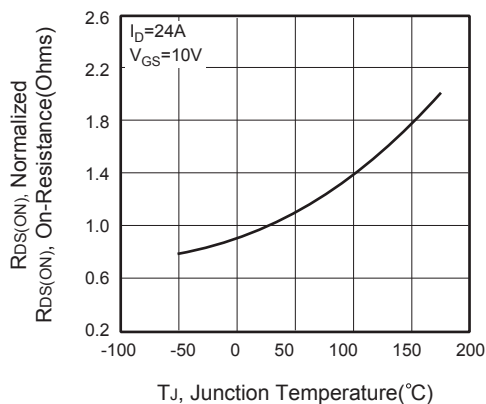


Figure 4. On-Resistance Variation with Temperature

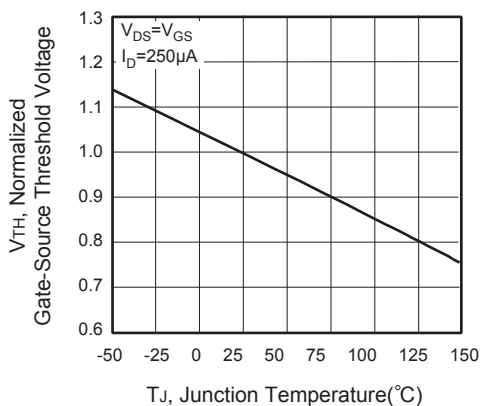


Figure 5. Gate Threshold Variation with Temperature

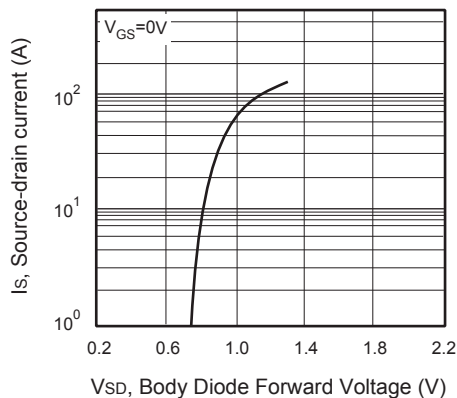


Figure 6. Body Diode Forward Voltage Variation with Source Current



CED6060R/CEU6060R

6

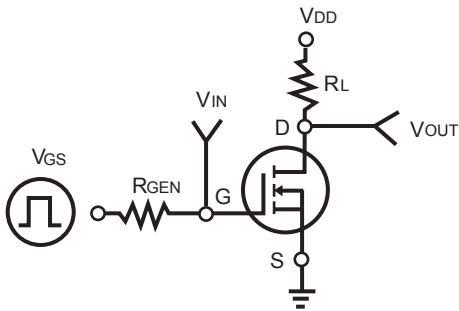
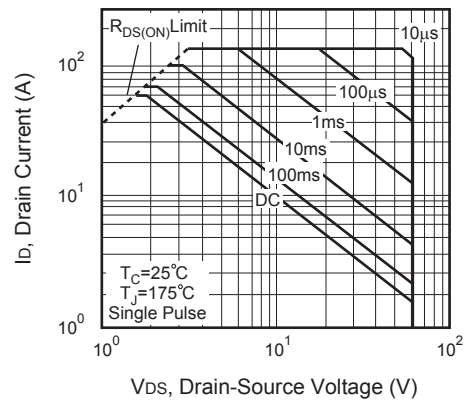
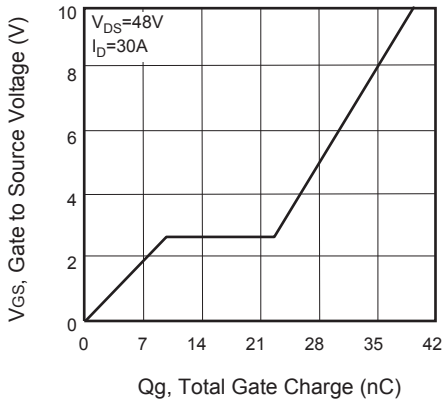


Figure 9. Switching Test Circuit

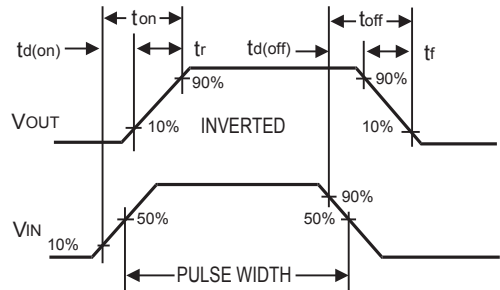


Figure 10. Switching Waveforms

